

Collaborative Alliance for Semiconductor Test (CAST)



Welcome to the CAST
kickoff meeting



CAST agenda

- 9:00 Welcome and introductions - John Adams, Teradyne
- 9:15 Keynote of trends and need for CAST, cooperation & standardization – Omer Dossani, Senior Director of Test PLM, STATSChipPAC, Inc.
- 9:45 Vision, charter & how we got here. - Don Edenfeld, Intel
- 10:15 Break
- 10:30 Brief overview of areas of focus, direction of breakouts, prioritization of opportunities - Mark Roos, Roos Instruments
- 11:00 Update on status of current initiatives – Breakout session leaders
- 11:30 Panel discussion of focus areas, leading into idea generation for standards consideration (interactive dialogue between panel & audience) - Don E. (Intel), Omer (STATS ChipPAC), and John A. (Teradyne)
- 12:30 Lunch
- 1:30 **Breakout sessions:**
- Docking and Mounting – John Adams, Teradyne
 - Test Cell Communication, including SECS/GEM Standards - Len VanEck, LTX-Credence
 - STIL: Common Dialects - Paul Roddy, Advantest
 - Common STDF Format & Customization Syntax/API - AJ Khoche, Verigy
 - Yield Enhancement - Keith Arnold, PinTail technologies
 - Bench top and PTIM Standards - Luke Schreier, National Instruments
- 3:30 Reconvene
- 4:00 Adjourn

Industry Need

- Today's economic crisis and the industry's quest for lower "cost of test" has created a stronger push for greater collaboration in the semiconductor test industry.
- The absence of a SEMI NA Standards ATE Committee has resulted in standards development by multiple ad hoc groups:
 - STC (Semiconductor Test Consortium) www.semitest.org
 - STDF Group <http://stdf.bcsweb.com>
 - T2C2 (Test Technology Collaboration Consortium) www.t2c2.org
- It is getting difficult to follow the many groups that are supporting the semiconductor test community

Strong interest as evidenced by today's participation

- **Optimal Test**
- **iSoft Consulting Group**
- **Pintail Technologies**
- **National Instruments**
- **Advantest**
- **Roos Instruments**
- **inTEST**
- **Maxim**
- **AEHR Test Systems**
- **ASE**
- **Intel**
- **LTX-Credence**
- **Teradyne**
- **Verigy**
- **Zenpire Corporation**
- **Centipede Systems, Inc.**
- **STATS ChipPAC, Inc.**
- **Nanometrics**
- **Electroglas**
- **Kinesys Software, Inc.**
- **Wright, Williams, and Kelly, Inc.**
- **Synopsys**
- **Simutest, Inc.**
- **MicroHandling, GmbH**
- **Liberty Research**
- **InfraStructure Advisors**
- **Event Based Technologies (PTE) Ltd. (EBT)**
- **KVD**
- **SUNRGI**
- **Test Advantage**
- **SV Probe**
- **Tokyo Electron America, Inc.**
- **Salland Engineering (North America), Inc.**
- **Johnstech**
- **Scanimetrics, Inc.**
- **Salvador & Smith Associates**
- **WL Gore & Associates**
- **LSI**
- **KLA-Tencor**
- **Aeroflex International, Ltd.**
- **IEEE**
- **GE Global Electronics Services**
- **nVidia**
- **KYEC**

Background

- The STC initiated the effort to form a new global CAST (Collaborative Alliance for Semiconductor Test) organization, with a goal to:
 - Have full industry representation
 - Move under an existing established industry organization

- CAST founding members include:
 - Advantest
 - Amkor
 - Infineon
 - Intel
 - LTX-Credence
 - Qualcomm
 - Roos
 - Teradyne
 - Verigy

- CAST charter includes:
 - Foster pre-competitive collaboration
 - Research, develop and promote standards that enable industry productivity improvements
 - Perform pre-competitive benchmarks
 - Act as a representative and an advocate for the members

Background

- CAST was formed in 2008 and moved under SEMI as a SIG (Special Interest Group) in January, 2009
- One of CAST's reasons for selecting SEMI as a host organization was SEMI's formal, mature standards process
- CAST is consolidating other industry working groups that were in operation, and is looking to form new additional working groups.
- CAST is now asking for formation of a standards committee to support these working group activities.

CAST 2009 Calendar of Events

Activity	Location	Date
SEMICON West –Test Day, Workgroup meetings	San Francisco	July 14
Global CAST meeting	SEMI, San Jose	Oct. 6
ITC – STIL/STDF workgroup meetings	Austin	Nov. 6
SEMICON Japan, workgroup meetings	Japan	Dec. 2
TBD	Europe	TBD

Keynote Address

- Test technology trends and the need for CAST, cooperation, and standardization
 - Omer Dossani
 - *Senior Director of Test PLM, STATSChipPAC, Inc.*